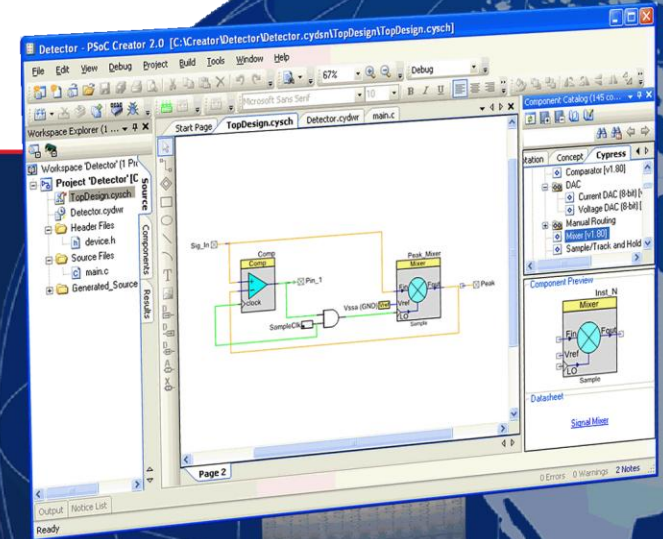


# Asynchronous SRAM With ECC Solution Examples

ECC = Error-Correcting Code

High-Speed and Low-Power Asynchronous SRAMs  
With On-Chip ECC to Improve System Reliability



# MoBL<sup>®1</sup> SRAM With ECC<sup>2</sup> Solution Example – Multi-Function Printer (MFP)



## MoBL SRAM With ECC Value

### Design Challenges

Write configuration and status data at access times of 45 ns  
Retain the data with battery back-up on power loss  
Provide error detection and correction to ensure data reliability

### MoBL SRAM With ECC Solution

Provides SRAM memory with 45-ns access time  
Provides 1- $\mu$ A/Mb standby current for long battery life  
Provides on-chip ECC with a FIT<sup>3</sup> rate of <0.1 FIT/Mb

## Suggested Collateral

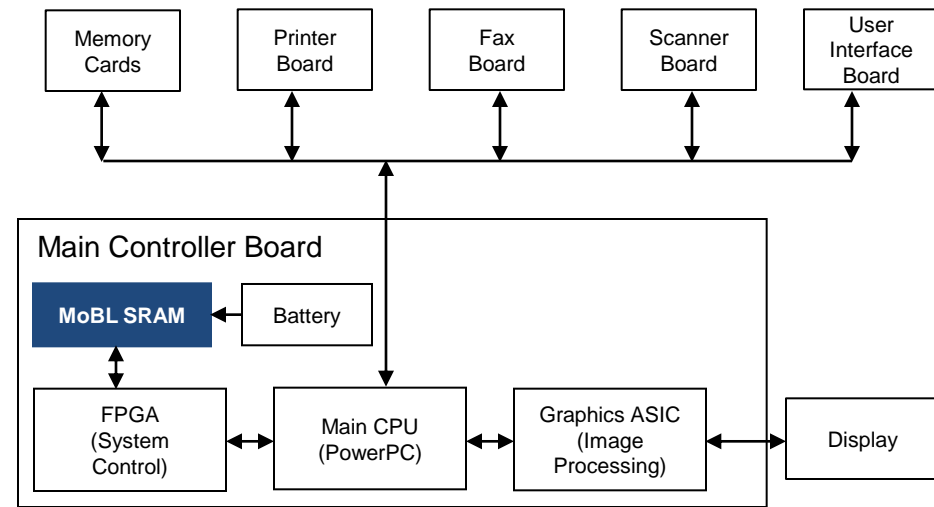
Application Notes: [MoBL SRAM application notes](#)  
Knowledge Base Articles: [MoBL SRAM articles](#)  
Datasheets: [MoBL SRAM datasheets](#)

## Discovery Questions

How do you retain the MFP's configuration and status data on power loss?  
How important is memory power consumption for your system?  
Is system reliability and soft-error<sup>4</sup> mitigation a critical concern?

## Block Diagram

### MoBL SRAM With ECC Solution for Multi-Function Printer



## Multi-Function Printer By Canon

Incorporates multiple functions (email, fax, photocopier, printer and scanner)



<sup>1</sup> Low-power Asynchronous SRAMs with less than 1- $\mu$ A/Mb standby current

<sup>2</sup> Encoding and decoding of a bit stream using extra bits to detect and correct bit errors

<sup>3</sup> Failure in Time: A reliability measurement of the projected failure rate of a device. One FIT equals one projected failure per billion device-hours

<sup>4</sup> A data error caused by background radiation

# Fast<sup>1</sup> SRAM With ECC<sup>2</sup> Solution Example – Programmable Logic Controller



## Fast SRAM With ECC Value

### Design Challenges

Write real-time data at access times as fast as 10 ns  
Provide error detection and correction to ensure data reliability  
Require a reliable and cost-effective memory solution

### Fast SRAM With ECC Solution

Provides 10-ns access time  
Provides on-chip ECC with a FIT<sup>3</sup> rate of <0.1 FIT/Mb  
Provides on-chip ECC, reducing board space and cost

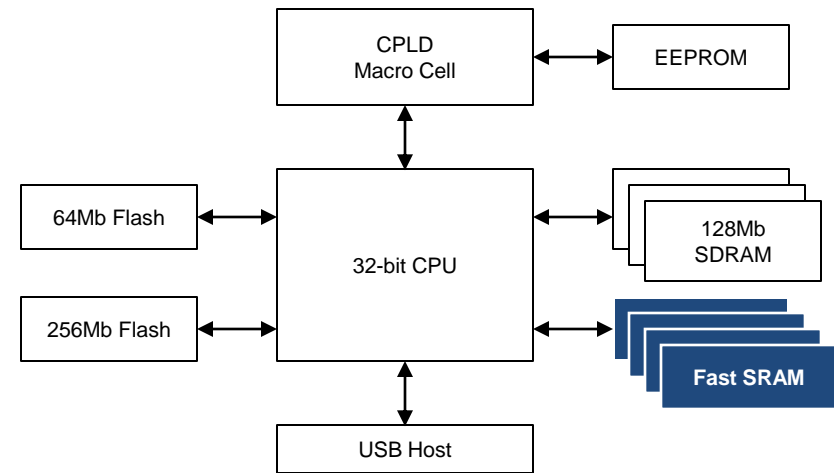
## Suggested Collateral

Application Notes: [Fast SRAM application notes](#)  
Knowledge Base Articles: [Fast SRAM articles](#)  
Datasheets: [Fast SRAM datasheets](#)

## Discovery Questions

What memory solution are you using for program execution?  
How important is memory access time for your system?  
Are system reliability and soft-error<sup>4</sup> mitigation a critical concern?

## Block Diagram



Programmable Logic Controller  
By Siemens



<sup>1</sup> High-speed Asynchronous SRAMs with access times  $\leq 20$  ns

<sup>2</sup> Encoding and decoding of a bit stream using extra bits to detect and correct bit errors

<sup>3</sup> A reliability measurement of the projected failure rate of a device. One FIT equals one projected failure per billion device-hours

<sup>4</sup> A data error caused by background radiation